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WHAT IS CLAIMED IS:

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fig.12.E

1. A semiconductor device comprising:

a substrate having a front surface and a rear surface;

an insulating film comprising aluminum nitride provided on said rear surface of the substrate; and

a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween

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2. A semiconductor device comprising:

a substrate having a front surface and a rear surface;

an insulating film comprising aluminum, nitrogen and oxygen

provided on said rear surface of the substrate; and

a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween.

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3. A semiconductor device comprising:

a substrate having a front surface and a rear surface;

an insulating film comprising aluminum nitride provided on

said rear surface of the substrate; and

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a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween,

wherein said insulating film comprising aluminum nitride has a thermal conductivity of 0.6 W/cm·K or higher.

4. A semiconductor device comprising:

a substrate having a front surface and a rear surface;

a multi-layer insulating film provided on said rear surface of the substrate and comprising an aluminum nitride layer and a silicon oxide layer, said aluminum nitride layer and said silicon oxide layer being provided adjacent to each other; and

a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween.

5. An active matrix type liquid crystal display comprising:
a substrate having a front surface and a rear surface;
an insulating film comprising aluminum nitride provided on said rear surface of the substrate; and

a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation

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region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween.

An active matrix type liquid chystal display comprising: 6. a substrate having a front surface and a rear surface; an insulating film comprising aluminum, nitrogen and oxygen provided on said rear surface of the substrate; and

a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween.

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7. An active matrix type liquid crystal display comprising: a substrate having a front surface and a rear surface; an insulating film comprising aluminum nitride provided on said rear surface of the substrate, and

a transistor provided over said front surface of the substrate, said transistor having at least a charmel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween wherein said insulating film comprising aluminum nitride has a thermal conductivity of 0.6 W/cm·K or higher.

8. An active matrix type liquid crystal display comprising: a substrate having a front surface\and a rear surface;

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a multi-layer insulating film provided on said rear surface of 112 let the substrate and comprising an aluminum nitride layer and a silicon oxide layer, said aluminum nitride layer and said silicon oxide layer being provided adjacent to each other; and

> a transistor provided over said front surface of the substrate, said transistor having at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation region with said gate insulating film interposed therebetween.

> An active matrix type liquid crystal display comprising: 9. a substrate having an insulating film comprising aluminum nitride outside said substrate, and having a transistor inside said substrate, wherein said transistor has at least a channel formation region comprising crystalline silicon, a gate insulating film adjacent to said channel formation region, and a gate electrode adjacent to said channel formation

- The device of claim 1 wherein said substrate is a glass 10. substrate.
- 11. The device of claim 2 wherein said substrate is a glass 20 substrate.

region with said gate insulating film interposed therebetween.

12. The device of claim 3 wherein said substrate is a glass substrate.

- 13. The device of claim 4 wherein said substrate is a glass substrate.
- 14. The display of claim 8 wherein said substrate is a glass substrate.

The display of claim 6 wherein said substrate is a glass substrate.

- 16. The display of claim 7 wherein said substrate is a glass substrate.
- 17. The display of claim 8 wherein said substrate is a glass substrate.
 - 18. The display of claim 9 wherein said substrate is a glass substrate.

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